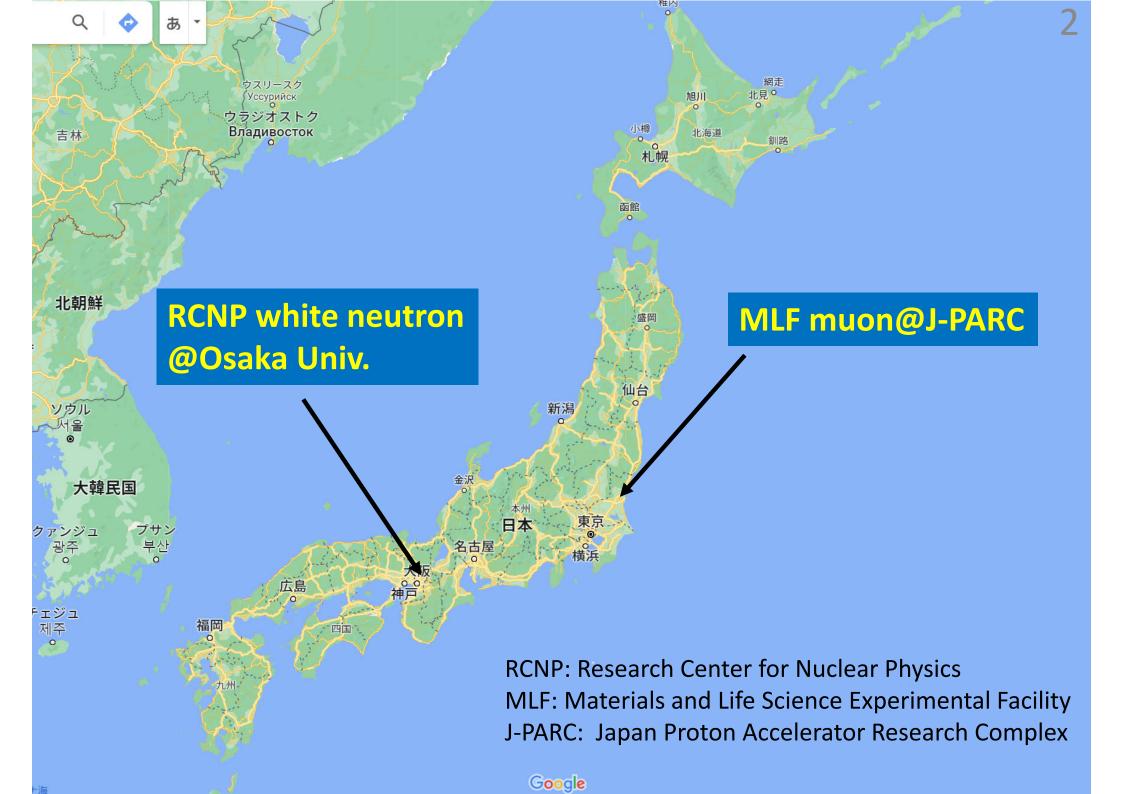
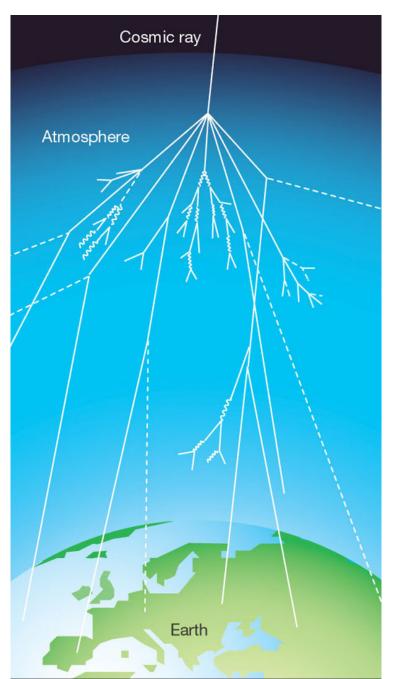
Terrestrial Cosmic-Ray SEE testing

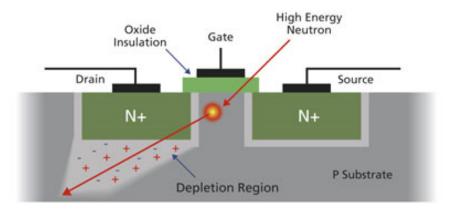
Masanori Hashimoto Kyoto University hashimoto@i.kyoto-u.ac.jp https://sites.google.com/view/masanorihashimoto/



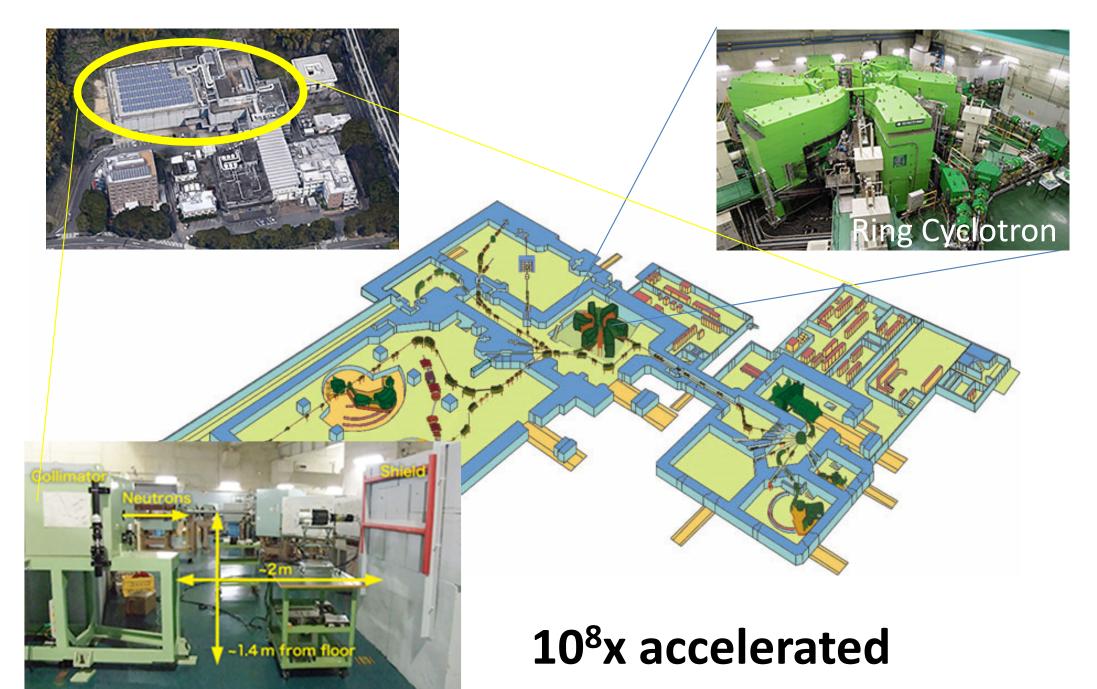
Neutron at terrestrial environment



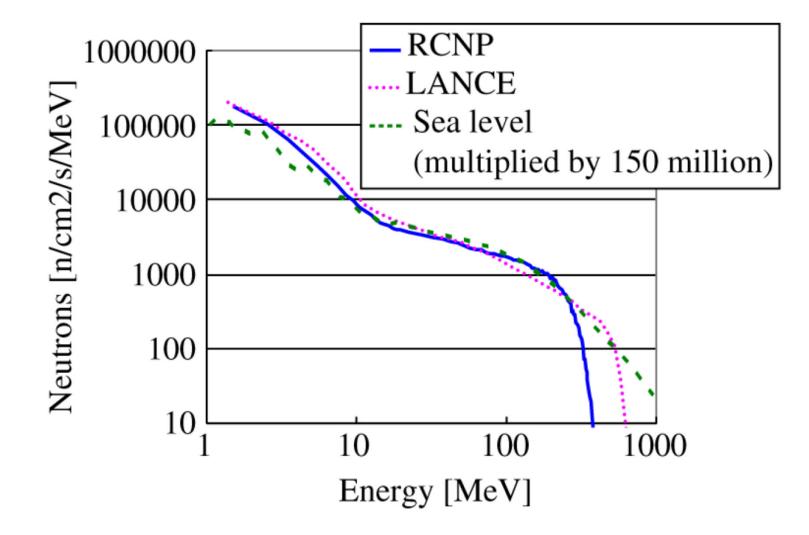
- Cosmic ray induces neutrons
- Nuclear reaction in silicon generates secondary ions and injects charge



White Neutron Test at RCNP



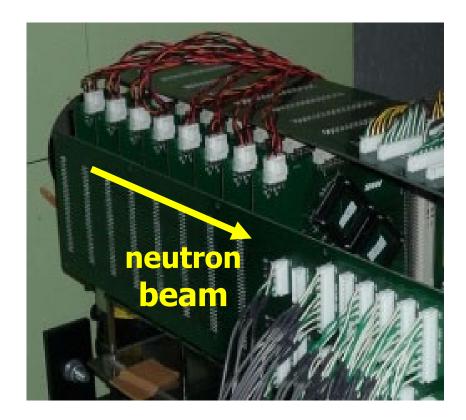
Neutron Energy Spectrum



Neutrons are generated by 400MeV protons

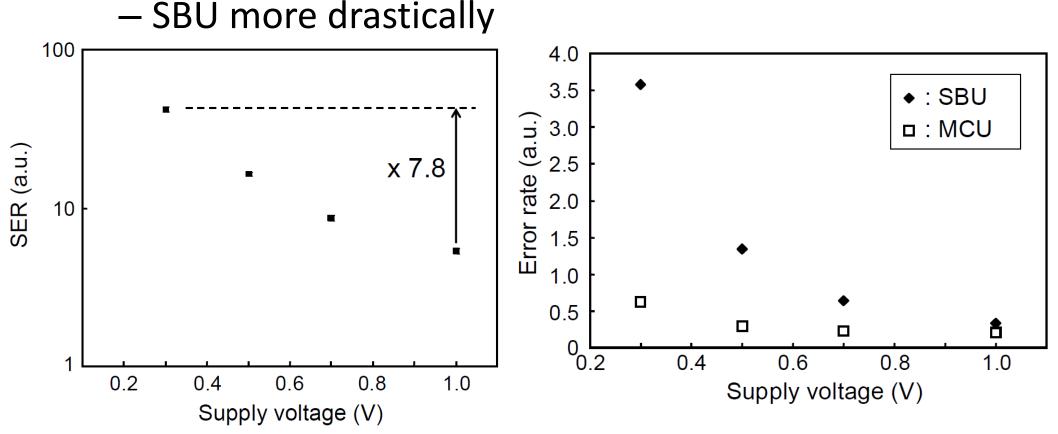
Setup example

- Neutron irradiation test was performed at RCNP
 - Flux of wide spectrum neutron beam is $2.41 \times 10^9 \text{cm}^{-2}\text{h}^{-1}$



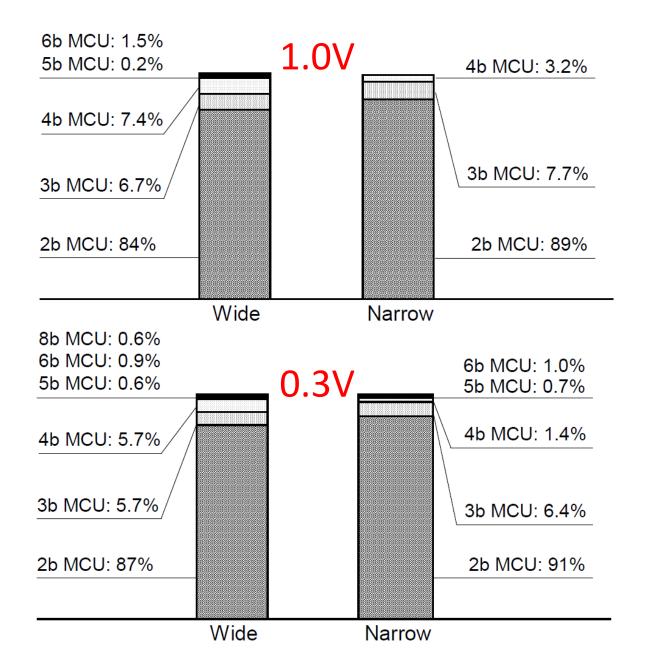
VDD Dependency of SBU and MCU

- Compared to 1.0V, SER at 0.3V is 7.8x higher
- Both SBU and MCU increase as Vdd decreases



H. Fuketa, M. Hashimoto, Y. Mitsuyama, and T. Onoye, ``Neutron-Induced Soft Errors and Multiple Cell Upsets in 65-nm 10T Subthreshold SRAM,'' *IEEE Trans. Nuclear Science*, vol. 58, no. 4, pp. 2097--2102, August 2011.

#Bits Distribution of MCU



MCU with large bits happens at low voltage.

Simple ECC could be insufficient.

UPDATE at RCNP

- Accelerator renovation has finished in 2022 after long shutdown.
- Beam size expansion from Φ100mm to Φ300mm is scheduled in 2023.
- 10x beam intensity enhancement is scheduled in five years.

Muon: potential source of soft error

Muon accounts for 70% of secondary particles on earth

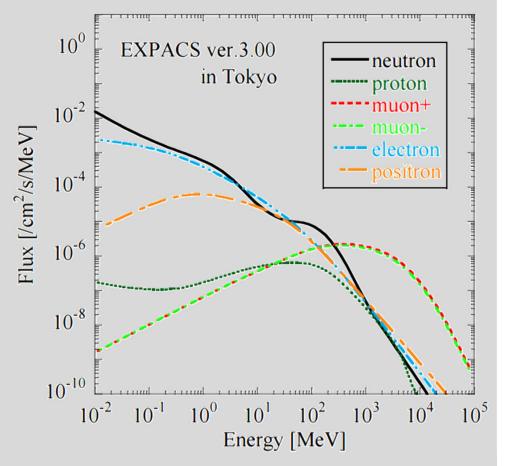


Fig. Flux spectra from EXPACS: T. Sato et al., EXPACS, *Radia. Res.*, 166, 544-555, 2006

Decrease in critical charge

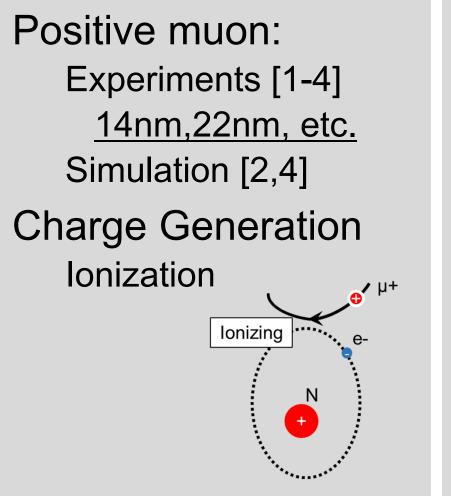
Deposited charge can exceed critical charge of modern devices!

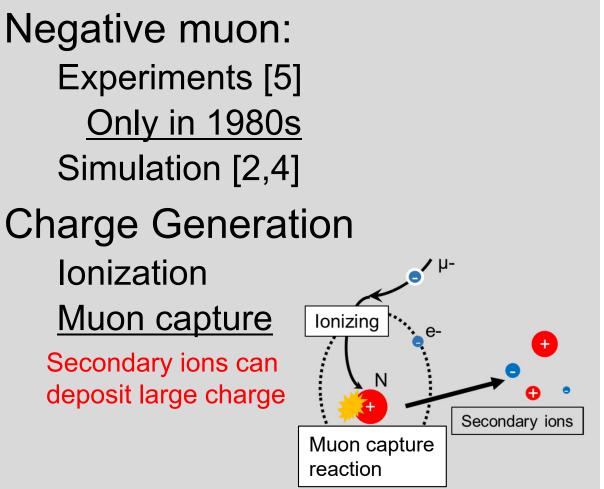
	1	
	$ \downarrow$	

Sensitive volume depth 0.5µm

Energy	dE/dx	Deposited Charge in 0.5µm
1GeV	0.47keV/µm	0.02fC
40KeV	73keV/µm	1.80fC

Previous works: muon-induced SEU





Impact of negative muon capture has not been studied in experiments.

[1],[2]: Sierawski et al., TNS, 2010 & IRPS, 2014,
[3]:Seifert: IRPS, 2015 [4]: S.Serre, RADECS, 2012 [5] :J. Dicello, Nucl. Inst. MPR, 1987

12 MUSE in J-PARC MLF 08 Entrance (for BL08, 09) 09 BL 09 BL 0 BL02 in entrance BL12 BL0 EN. ... A BL22 D2 BI 20 BL18 BL19

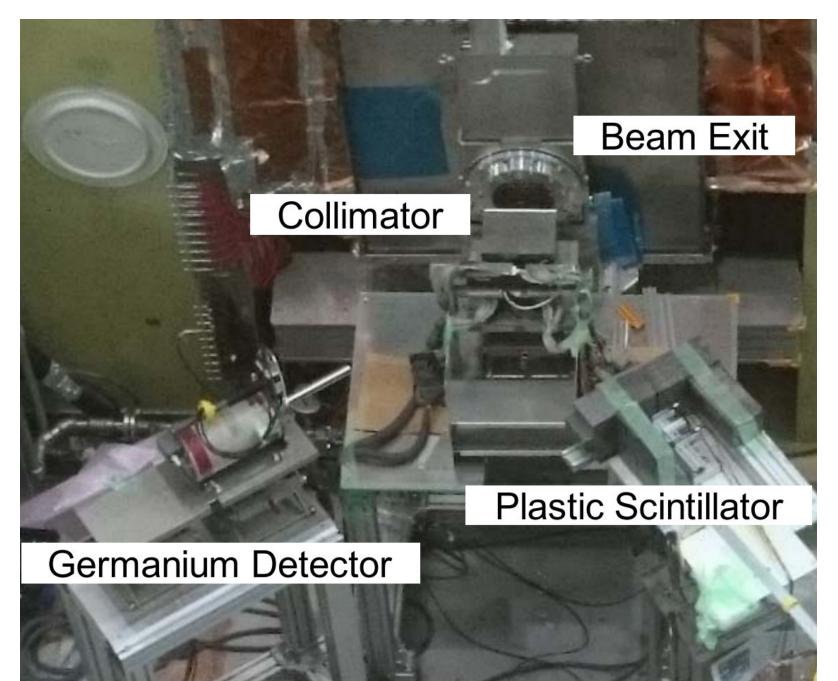
Muon beam at D2 line

High intensity for both positive and negative muons

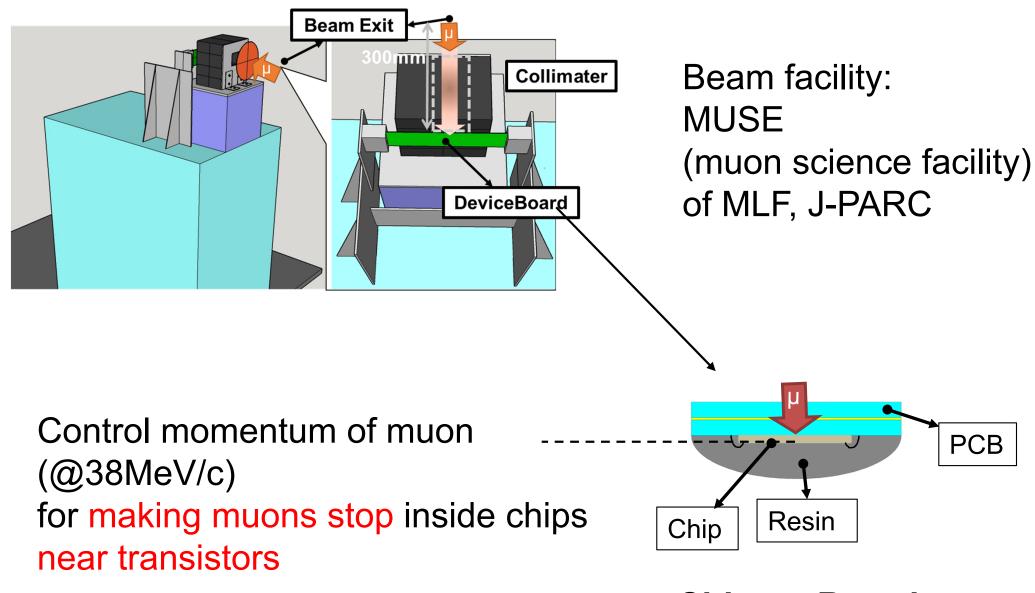
- Pions are first generated through nuclear reactions between a 3-GeV proton beam and a graphite target. The pions decay into muons in a superconducting solenoid magnet.
- Momentum < 50MeV/c
 - Momentum can be changed instantly
 - Momentum spreading σ =5%
- Pulsed beam (single or double, 25Hz)
- 8.0 \times 10⁶ µ/s (double pulse, in case of 800kW proton beam)

Setup example

S. Manabe, et al., "Negative and Positive Muon-Induced Single Event Upsets in 65-nm UTBB SOI SRAMs," IEEE TNS, Aug. 2018.

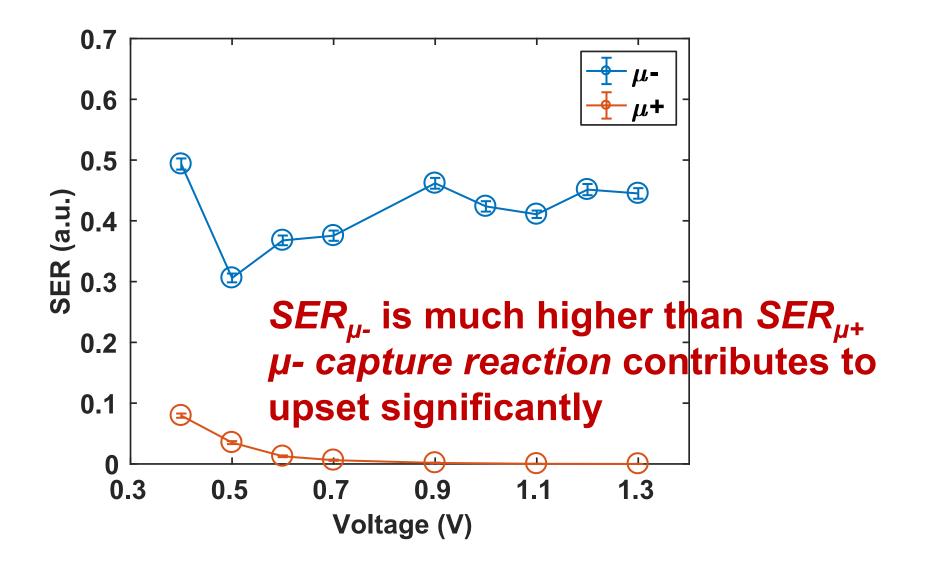


Experimental setup



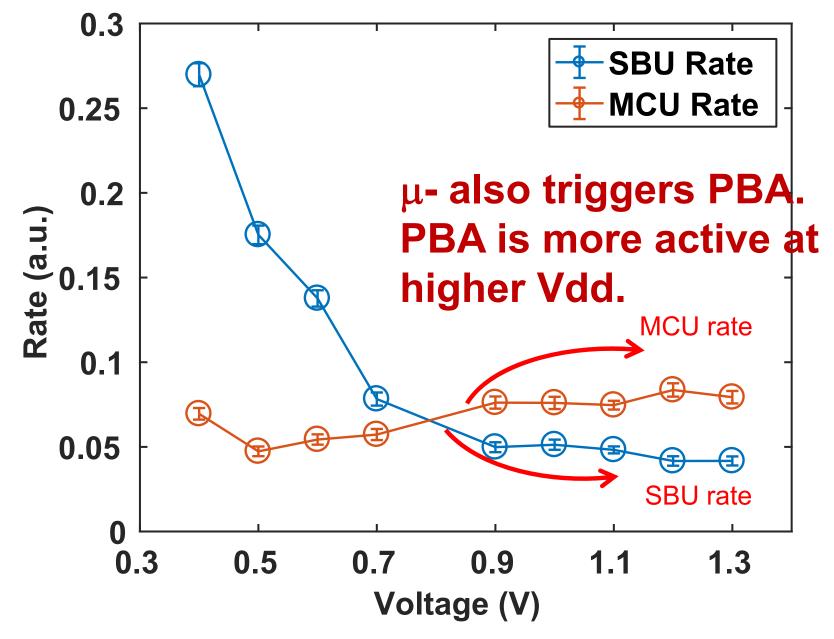
Chip on Board

Positive vs. negative muons in bulk



W. Liao, et al., "Measurement and Mechanism Investigation of Negative and Positive Muon-Induced Upsets in 65nm Bulk SRAMs," *IEEE Trans. Nuclear Science*, August 2018.

μ - MCU and SBU rates in bulk



 μ + cannot trigger PBA and its MCU rate is much lower than that of μ -

Conclusion

Introduced two facilities for terrestrial SEE testing

- RCNP white neutron @ Osaka Univ.
 - https://www.rcnp.osaka-u.ac.jp/index_en.html
 - White neutrons, 10⁸x accelerated
- MLF muon beam @ J-PARC
 - https://mlfinfo.jp/en/
 - Positive and negative muons, < 50MeV/c, 8.0 $\,\times\,$ 10^{6} μ/s

Both facilities are accepting proposals from all over the world.